Substitute	for Form 1449	PTO		Complete if Known					
	INFORI	MA.	TION DISCLOSURE	Application Number	10/665,970				
PE	\			Filing Date	September 18, 2003				
101 E	<b>S</b> XATE	ME	NT BY APPLICANT many sheets as necessary)		First Named Inventor:	Soma et al.			
/		use as	many sheets as necessary)		Art Unit	2863			
APR 2 4	.500g m			Examiner Name	Bryan Bui				
Sheet	(UUD gr)		of	2	Attorney Docket Number	4735.P005			
FRAF	U.S. PATENT DOCUMENTS								
Examiner Cite No. Initials*		Document Number		Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant			
			Number-Kind Code <sup>2</sup> (If known)	MM-DD-YYYY		Passages or Relevant Figures Appear			
141	1	US-	6,295,315 B1	09-25-2001	Frisch et al.				
		US-							
		US-							
		US-							
	-	US-							
		US-							
		US-							
		US-							
·	-	US-							
		US-			· · · · · · · · · · · · · · · · · · ·				
		US-							
		US-							
		US-							
		US-							
<del>-</del>									

FOREIGN PATENT DOCUMENTS								
Examiner Initials*	Cite No.1	Foreign Patent Document  Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>3</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T6		

Examiner Signature	1 des	Date Considered	5/3406

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. <sup>1</sup>Applicant's unique citation designation number (optional). <sup>2</sup>See Kinds Codes of USPTO Patent Documents at <a href="https://www.uspto.gov">www.uspto.gov</a> or MPEP 901.04. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>8</sup>Applicant is to place a check mark here if English language translation is attached. This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, Washington, DC 20231. DO NOT SENT FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, Virginia 22313-1450. If you need assistance in completing the form, call 1-800-PTO-9199 (1-800-786-9199) and select option 2.

Substitute for Form 1449/PTO					ı	Complete if Known			
INFORMATION DISCLOSURE					OSURE	Application Number	10/665,970		
STATEMENT BY APPLICANT						Filing Date	September 18, 2003		
						First Named Inventor:	Soma et al.		
•		(use as n	nany shee	ets as neces	sary)	Art Unit	2863		
						Examiner Name	Bryan Bui		
Sheet		2		of	2	Attorney Docket Number	4735.P005		
NON PATENT LITERATURE DOCUMENTS									
Initials* No <sup>1</sup> item (book, magazine, journal,				e name of m (book, n	nagazine, journal, sei	TAL LETTERS), title of the article (when appropriate), title of the erial, symposium, catalog, etc.), date, page(s), volume-issue olisher, city and/or country where published			
130	,	2	BOUWMAN, F. et al., "Application of Joint Time-Frequency Analysis in Mixed Signal Testing," Proc. IEEE International Test Conference, pp. 747-756, Washington, DC, 1994.						
		3		YAMAGUCHI, T.J. et al., "Dynamic Testing of ADCs Using Wavelet Transforms," Proc. IEEE International Test Conference, pp. 379-388, Washington, DC, 1997.					
		4	SUNTER, S. et al., "BIST for Phase-Locked Loops in Digital Applications," Proc. IEEE International Test Conference, pp. 532-540, Sept. 28-30, 1999, Atlantic City, NJ.						
		5	MASON, R. et al., "Mixed Signal DFT at GHz Frequencies," J. of Electronic Testing: Theory and Applications 15, pp. 31-39, 1999.						
		6	ROH, J. et al., "Subband Filtering Scheme for Analog and Mixed-Signal Circuit Testing," Proc. IEEE International Test Conference, pp. 221-229, Atlantic City, NJ, 1999.						
		7	YAMAGUCHI, T.J. et al., "Jitter Measurements of a PowerPC Microprocessor Using An Analytic Signal Method," Proc. IEEE International Test Conference, pp. 955-964, Atlantic City, NJ, 2000.						
		8	CHAN, A.H. et al., "A Synthesizable, Fast and High-Resolution Timing Measurement Device Using a Component-Invariant Vernier Delay Line," Proc. IEEE International Test Conference, pp. 858-867, Baltimore, MD, 2001.						
137	BHUNIA, S. et al., "Dynamic Supply Current Testing of Analog Circuits Using Wavelet Transform," Proc. IEEE VLSI Test Symposium, pp. 302-307, Monterey, CA, 2002.								
			-						

Examiner	77	Date	170/06
Signature	12	Considered	1/10/00

\*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. Applicant's unique citation designation number (optional). Applicant is to place a check mark here if English translation

ts attached.

This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, Washington, DC 20231. DO NOT SENT FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, Virginia 22313-1450.

If you need assistance in completing the form, call 1-800-PTO-9199 (1-800-786-9199) and select option 2.